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Patents

- 11,546,370 Anti-Replay Protection for Network Packet Communications; Millman, Torla, Abdoo, 2023
- 9,904,804 Layout-optimized random mask distribution system and method; Coric, Millman, 2018 (derivative of 9,118,441)
- 9,632,977 System and method for ordering packet transfers in a data processor; Boland, Harris, Millman, 2017
- 9,286,118 System and method for improved job processing to reduce contention for shared resources; Boland, Harris, Millman, 2016
- 9,158,499 Cryptographic processing with random number generator checking; Torla, Millman, Tkacik, Frank, 2015
- 9,118,441 Layout-optimized random mask distribution system and method; Coric, Millman, 2015
- 9,104,478 System and method for improved job processing of a number of jobs belonging to communication streams within a data processor; Boland, Harris, Millman, 2012
- 9,092,283 Systems with multiple port random number generators and methods of their operation; Tkacik, Abdoo, Brocker, Millman, 2015
- 8,938,072 Cryptographic key derivation device and method therefor; Coric, Millman, 2015
- 8,910,179 Systems and methods for providing semaphore-based protection of system resources; Millman, 2014
- 8,856,198 Random value production methods and systems; Abdoo, Brocker, Millman, Tkacik, 2014
- 8,826,391 Virtualized trusted descriptors; Tkacik, Covey, Hartley, Millman, 2014
- 8,413,153 Methods and systems for sharing common job information; Harris, Boland, Millman, 2013
- 7,970,087 Eye center determination system and method; Millman, 2011
- 7,917,831 Optimization of storage device accesses in RAID systems; Millman, Torla, 2011
- 7,668,274 Eye center retraining system and method; Millman, Mijuskovic, Porter, 2010
- 7,373,539 Parallel path alignment method and apparatus; Millman, 2008
- 6,374,203 Method of modeling circuit cells with distributed serial loads; Millman, Wloka, Tyler, 2002
- 5,631,962 Circuit and method of encrypting key validation; Balph, Millman, 1997
- 5,498,988 Low power flip-flop circuit and method thereof; Reyes, Millman, Tyler, 1996
- 5,410,548 Test pattern fault equivalence; Millman, 1995
- 5,406,216 Technique and method for asynchronous scan design; Millman, Balph;

1995

5,390,193 Test pattern generation; Millman, Garvey, 1995

5,128,555 Pulsed CMOS logic circuit having selectable rise and fall times, Millman, 1992

5,126,596 Transmission gate having a pass transistor with feedback; Millman, 1992

5,107,148 Bidirectional buffer having tri-state buffers for circuit isolation; Millman, 1992

Publications

“How to Achieve 95% Fault Coverage Without Really Trying,” IEEE Design & Test of Computers, Fall, 1996, Millman

“Standard Cell Library Characterization for Setting Current Limits for IDDQ Testing,” 1996 IEEE International Workshop on IDDQ Testing, Millman and Acken

“Current Measurement Data to Demonstrate Setting Current Limits in a Complete IDDQ Testing Methodology,” 1995 IEEE International Workshop on IDDQ Testing, Acken and Millman

“Improving Quality: Yield Versus Test Coverage,” Economics of Electronic Design, Manufacture, and Test, 1994, Millman

“Improving Quality: Yield Versus Test Coverage,” Journal of Electronic Testing, May 1994, Millman

“Diagnosing CMOS Bridging Faults with Stuck-At, IDDQ, and Voting Model Fault Dictionaries,” IEEE 1994 Custom Integrated Circuits Conference, Millman and Acken

“Special Applications of the Voting Model for Bridging Faults,” IEEE Journal of Solid-State Circuits, March 1994, Millman and Acken

“WSI Evolution: Increasing Cell Size to Generalize Designs,” Sixth Annual IEEE International Conference on Wafer Scale Integration 1994, Millman

“Visualizing Test Information: A Novel Approach for Improving Testability,” International Test Conference, 1993, Moorman and Millman

“Improving Quality: Yield Versus Test Coverage,” Second International Workshop on the Economics of Design, Test & Manufacturing for Electronic Circuits and Systems, May 1993, Millman

“Special Applications of the Voting Model for Bridging Faults,” IEEE 1993 Custom Integrated Circuits Conference, Millman and Acken

“Improving Quality: Yield Versus Test Coverage,” International Conference on Wafer Scale Integration, 1993, Millman

“Fault Model Evolution for Diagnosis: Accuracy Versus Precision,” IEEE 1992 Custom Integrated Circuits Conference, Acken and Millman

“An Accurate Bridging Fault Test Pattern Generator,” International Test Conference, 1991, Millman and Garvey

“Bridging, Transition, and Stuck-Open Faults in Self-Testing CMOS Checkers,” Twenty-First International Symposium on Fault-Tolerant Computing, 1991, Millman and McCluskey

“Accurate Modeling and Simulation of Bridging Faults,” Custom Integrated Circuits Conference, 1991, Acken and Millman

“Diagnosing CMOS Bridging Faults with Stuck-At Fault Dictionaries,” International Test Conference, 1990, Millman, Acken, and McCluskey

“Detecting Stuck-Open Faults with Stuck-At Test Sets,” IEEE 1989 Custom Integrated Test Conference, Millman and McCluskey

Nonclassical Faults in CMOS Digital Integrated Circuits, PhD Dissertation, Stanford University, 1989, Millman

Detecting Bridging Faults with Stuck-At Test Sets,” International Test Conference, 1989,
Millman and McCluskey